

<b>Search Notes</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10587010	KUMAKI ET AL.
Examiner	Art Unit	
Dawn Garrett	1794	

### SEARCHED

Class	Subclass	Date	Examiner

### SEARCH NOTES

Search Notes	Date	Examiner
EIC-1700 STIC structure search (see attached printout)	2/26/2009	D. Garrett

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

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